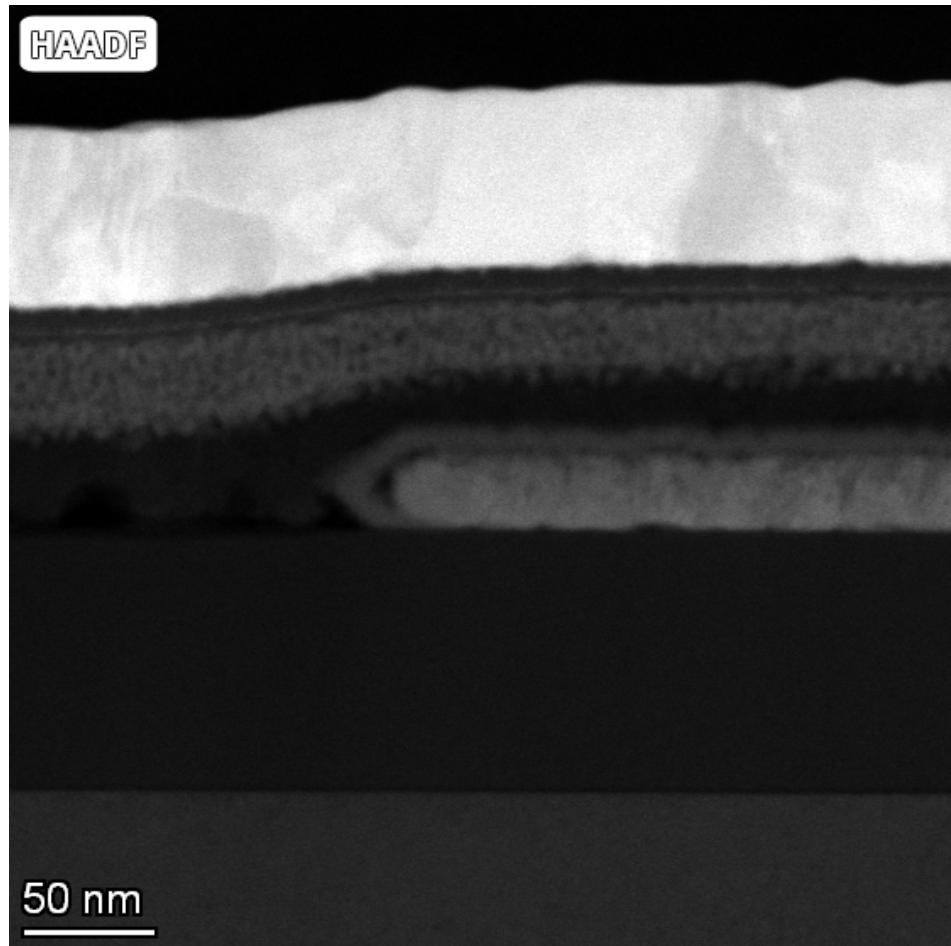


# Analytical TEM part I

**Duncan Alexander**  
EPFL-IPHYS-LSME

# EPFL Adding colour to microscopy!

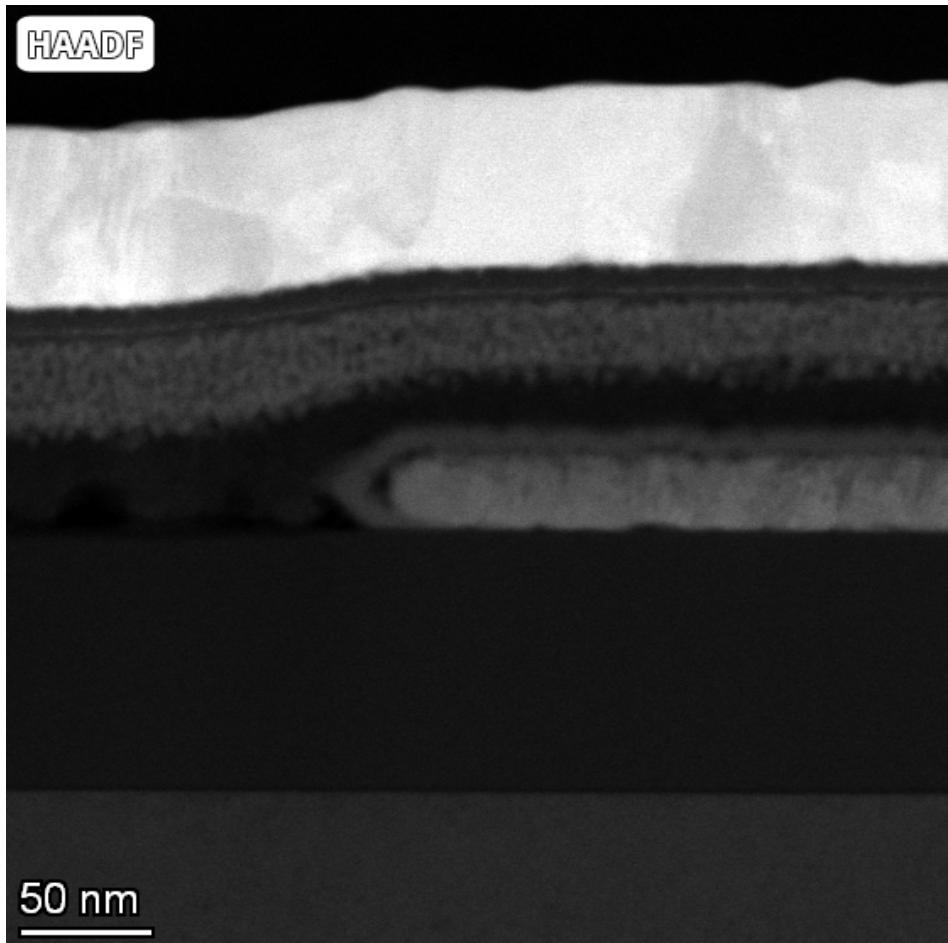
- Multilayer from first STEM lecture



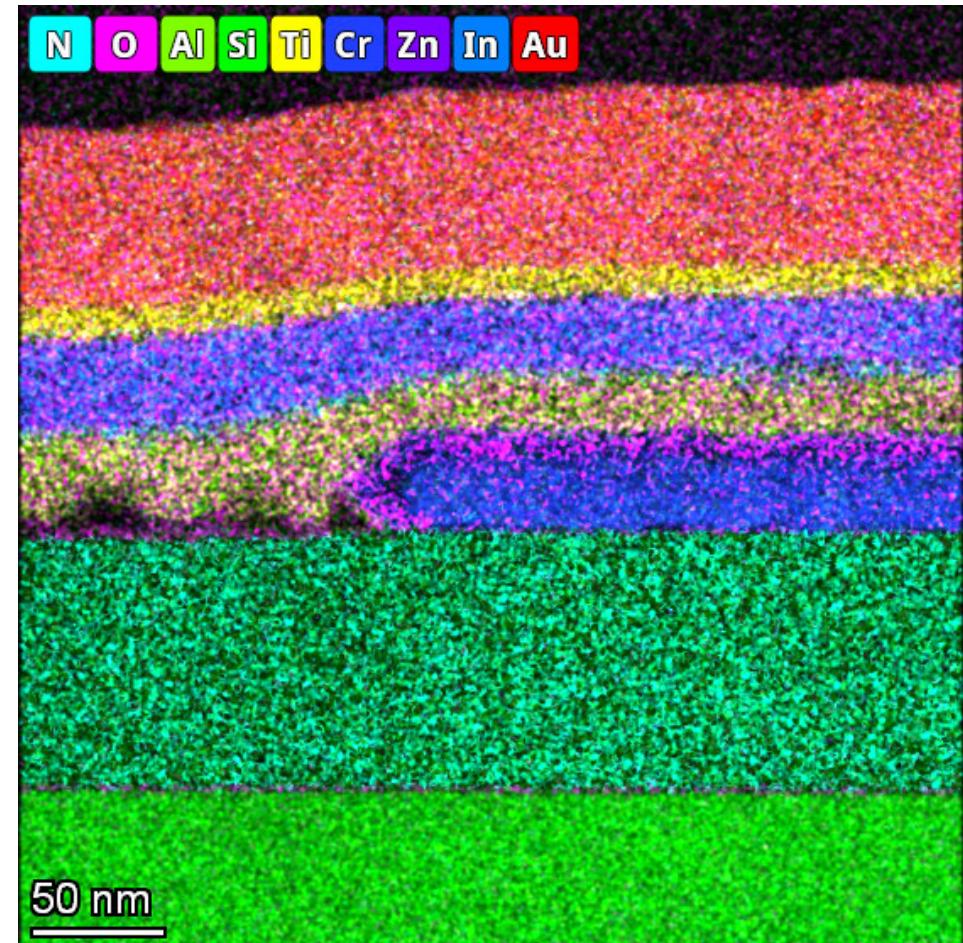
$$I \propto z^{1.6-1.9}$$

# EPFL Adding colour to microscopy!

- Multilayer from first STEM lecture



EDX spectroscopy



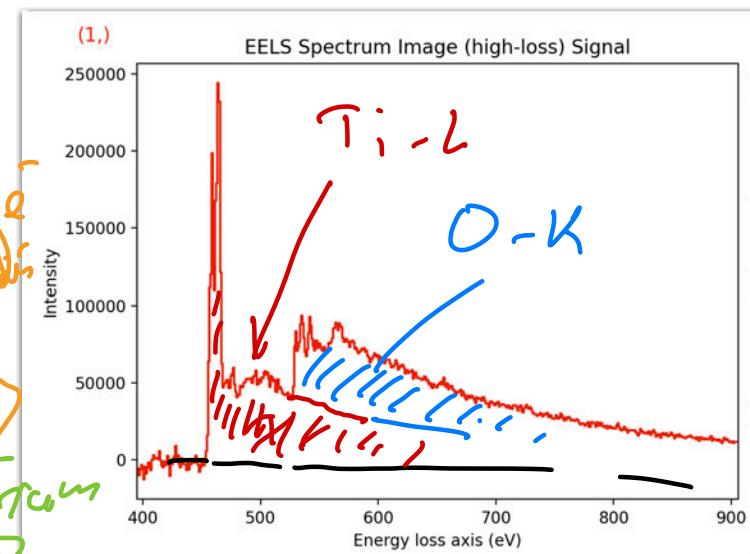
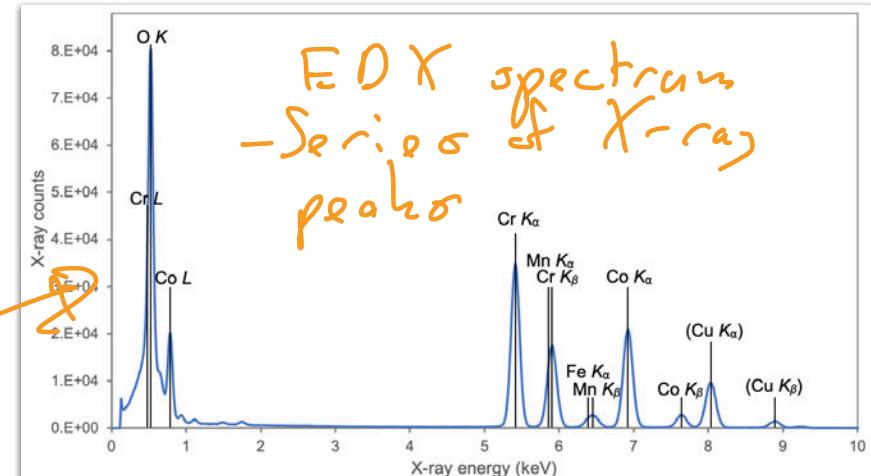
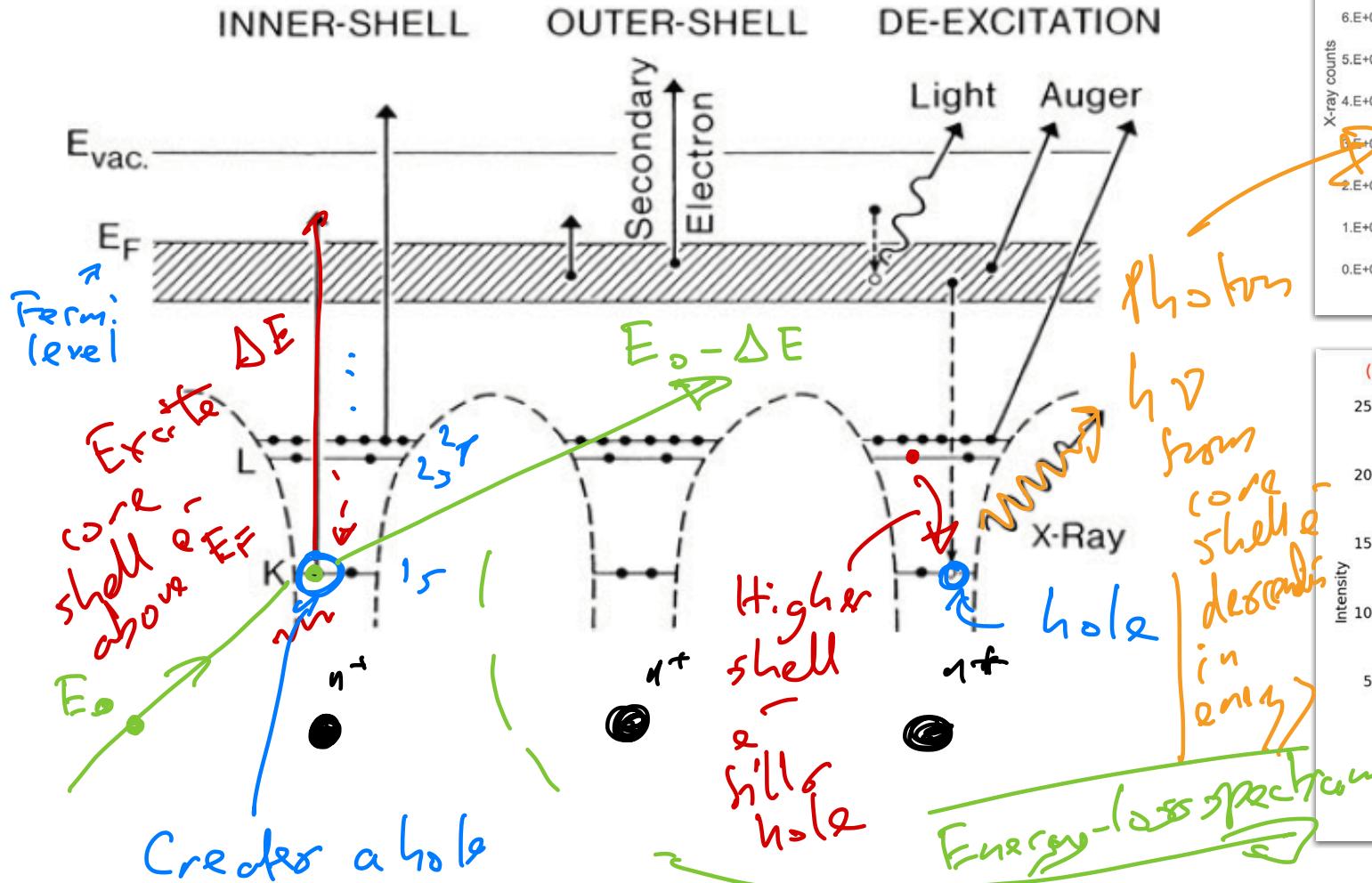
# EPFL Contents

- Introduction to EDX spectroscopy and EELS
- Energy dispersive X-ray (EDX) spectroscopy
  - X-ray generation
  - EDX spectrum
  - Detector setup
  - Applications

**EPFL** A way to probe chemistry

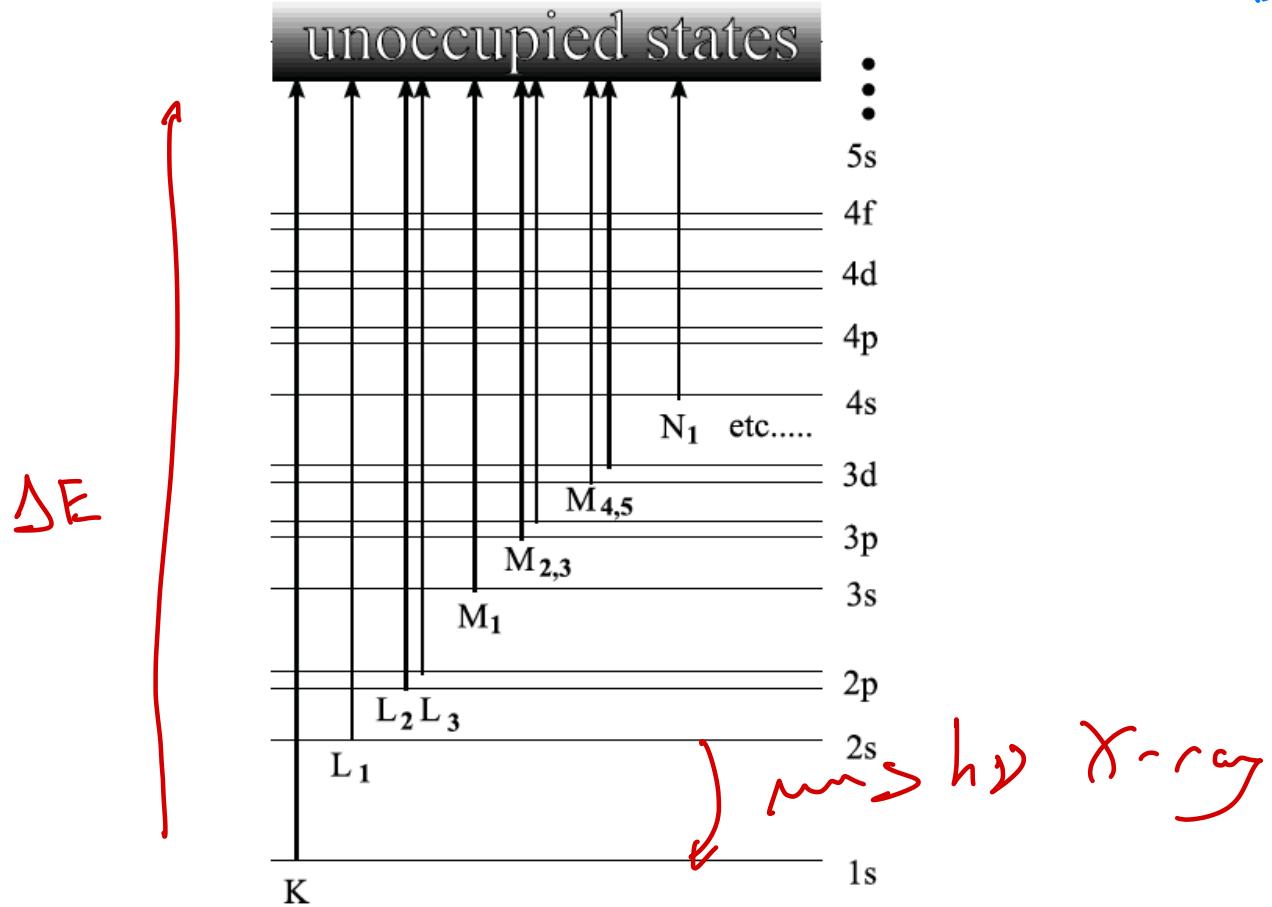
## [IONIZE ATOM]

Incident  $e^-$  energy  $E_0$   
 $E_0$ : 80-300 keV (from light tension)

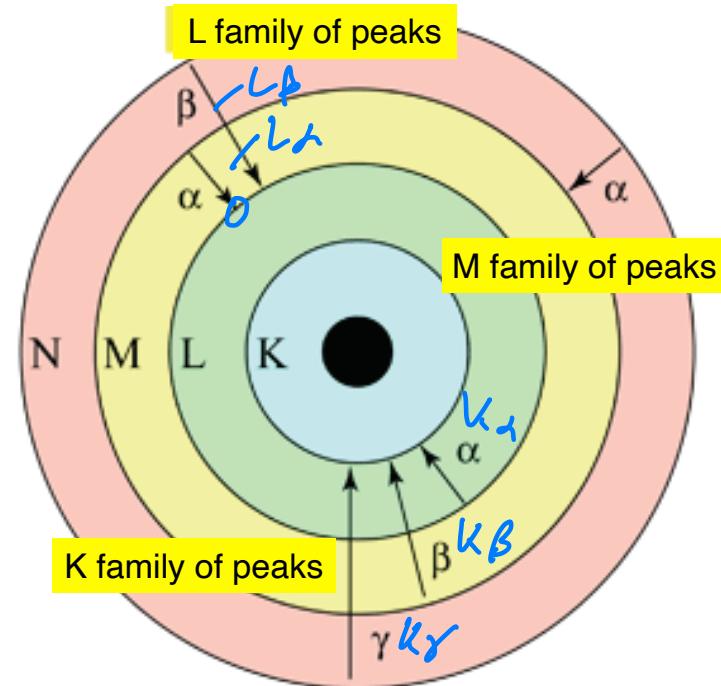


## Edges and peaks nomenclature

EELS



EDXS - X-ray transition

 $K_\alpha, K_\beta$  $L_\alpha, L_\beta$  $M_\alpha, \dots$

# EPFL Quiz

EDX, EDS, XEDS

/

- EDXS: energy dispersive X-ray spectroscopy  
⇒ intensity spectrum of X-ray peaks separated by energy
- EELS: electron energy-loss spectroscopy  
⇒ intensity spectrum of energy lost by transmitting  $e^-$   $(\Delta E)$
- We look at a sample containing Oxygen. We detect the Oxygen K-edge both in EELS and in EDXS. We find the transition at  $E_{EELS}$  in EELS and  $E_{EDXS}$  in EDXS
- Do we have:
  - 1)  $E_{EELS} > E_{EDXS}$
  - 2)  $E_{EELS} = E_{EDXS}$
  - 3)  $E_{EELS} < E_{EDXS}$

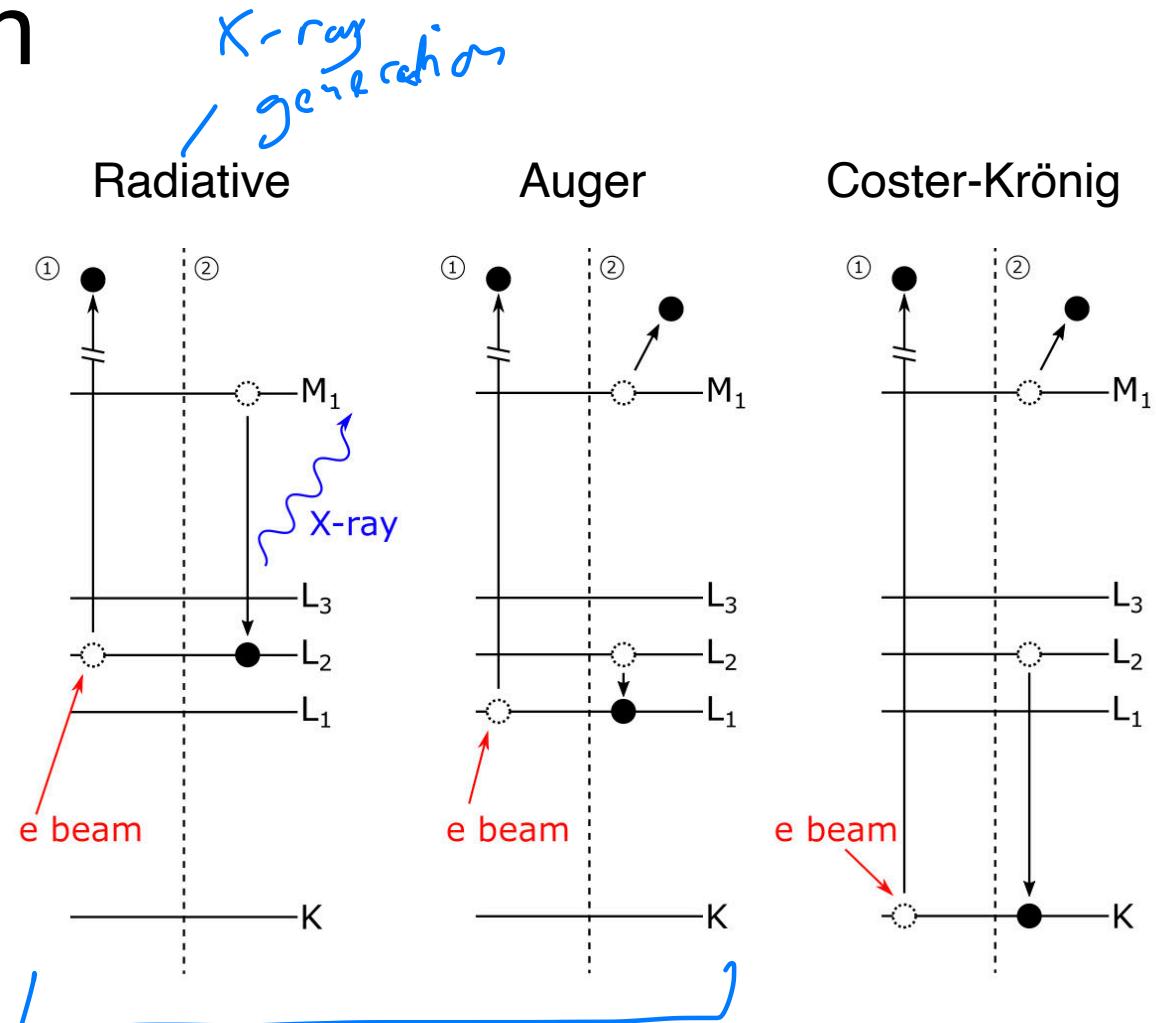
# EPFL Contents

- Introduction to EDX spectroscopy and EELS
- Energy dispersive X-ray (EDX) spectroscopy
  - X-ray generation
  - EDX spectrum
  - Detector setup
  - Applications

# EPFL X-ray generation

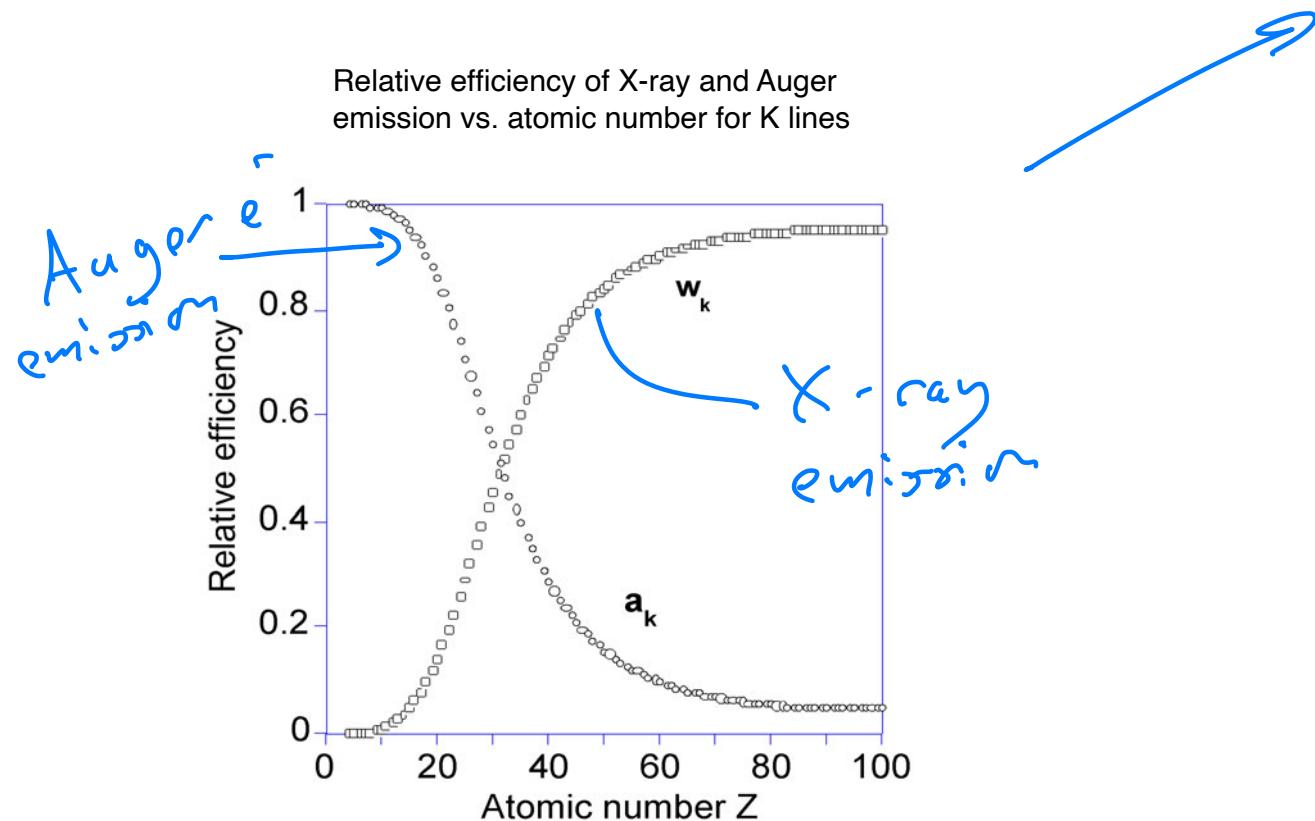
- 3 basic de-excitation process:
  - Radiative X-ray emission
  - Auger transitions/emission
  - Coster-Krönig transitions
- Complex “cascade” effects possible

Excitation probabilities  
can be calculated

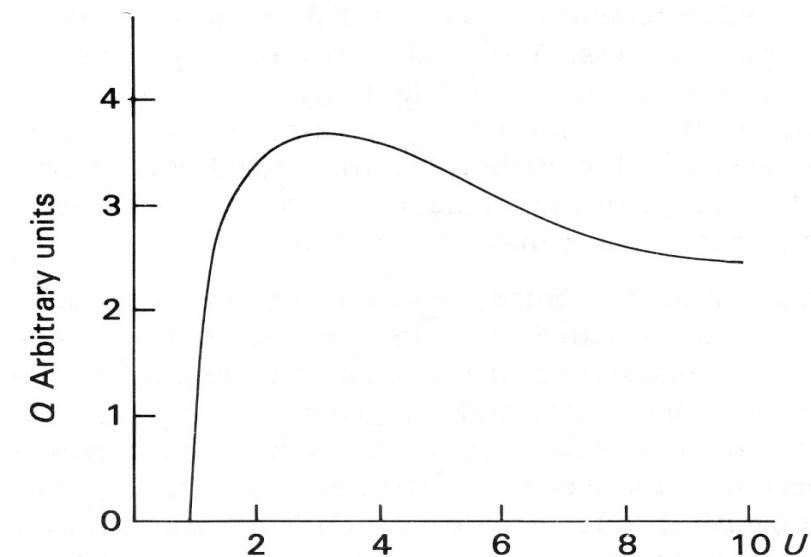
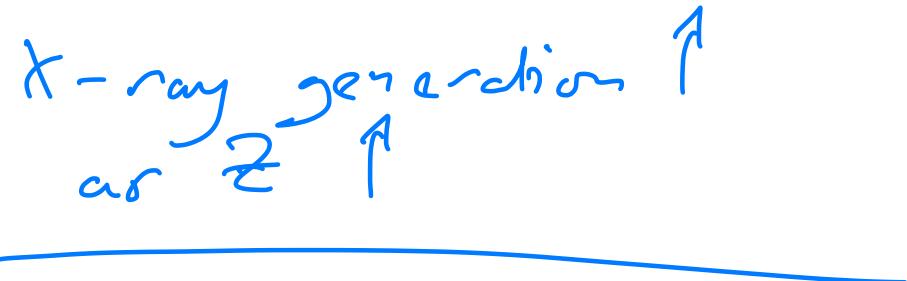


2 transitions  
“in competition”

# EPFL X-ray generation

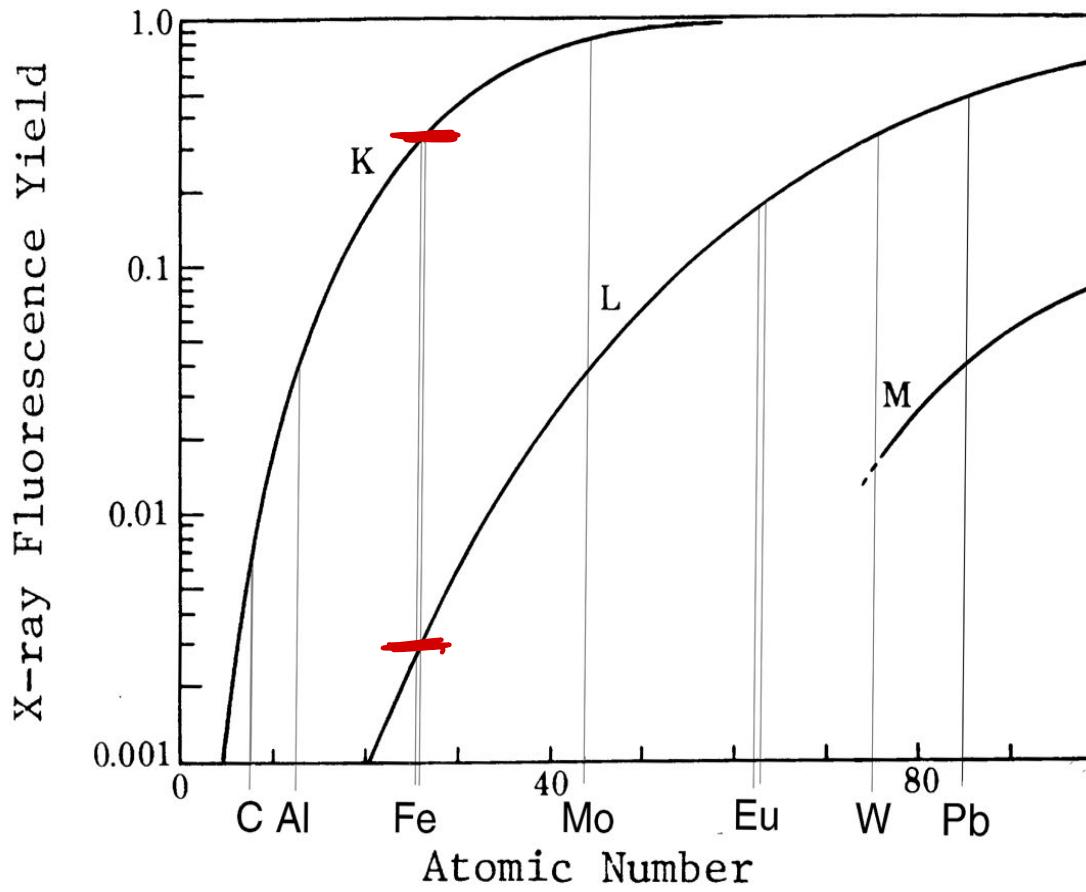


Light element atoms return to fundamental state mainly by Auger emission. For that reason, their K-lines are weak. In addition their low energy makes them easily absorbed.



To ionise an atom, the incident electron MUST have an energy larger than the core shell level  $U > 1$ . To be efficient, it should have about twice the edge energy  $U > 2$ .

(S)TEM:  $U \geq 60 \text{ keV}$   
 $\Rightarrow$  All X-ray excited



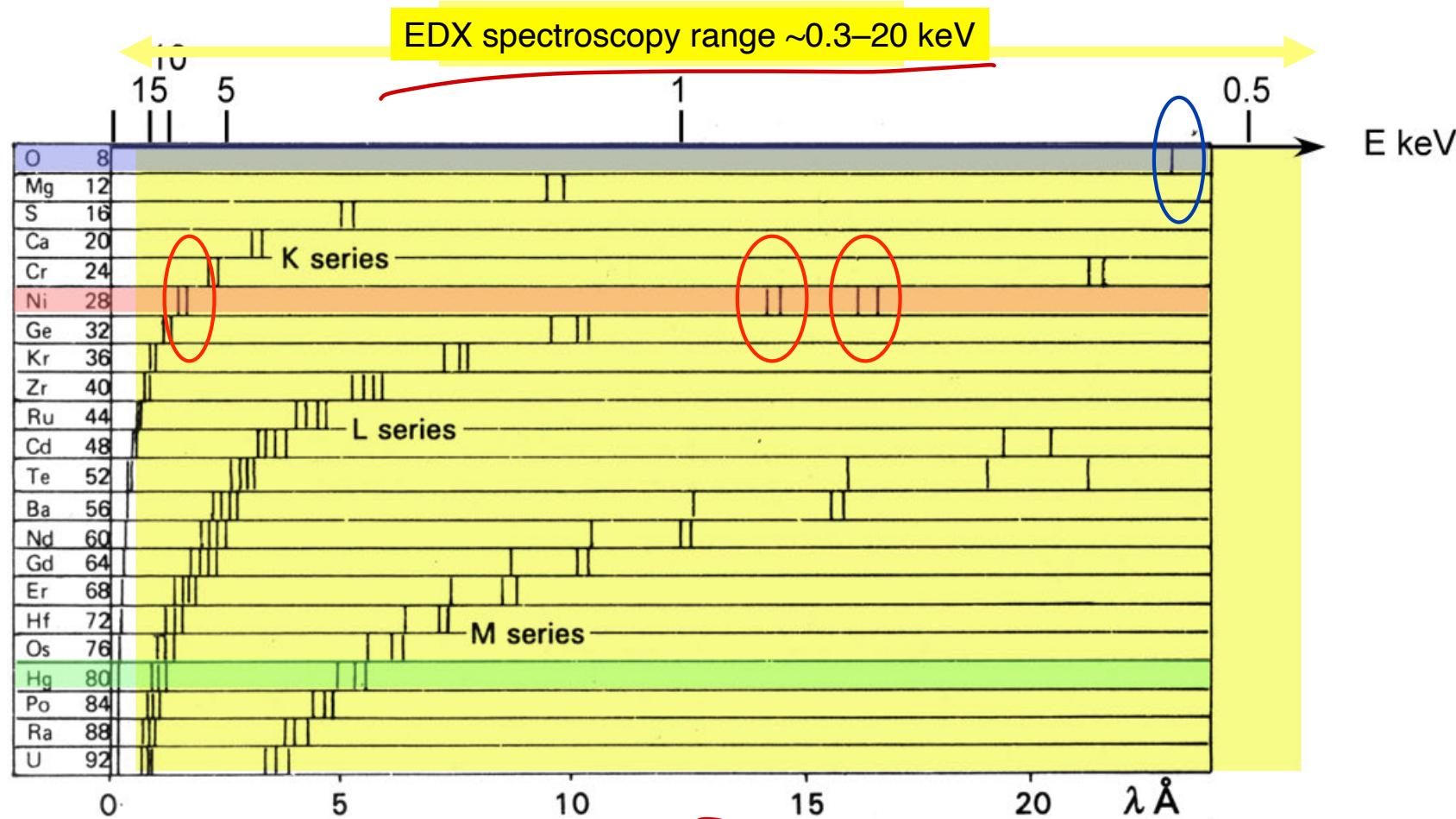
Probability of ionization  
+ prob. of de-excitation  
as X-ray emission

Peak intensity

For each  $Z$ :  
"Pixel" intensity ratio  
between their peaks  
e.g.  $K_{\alpha} : K_{\beta}$

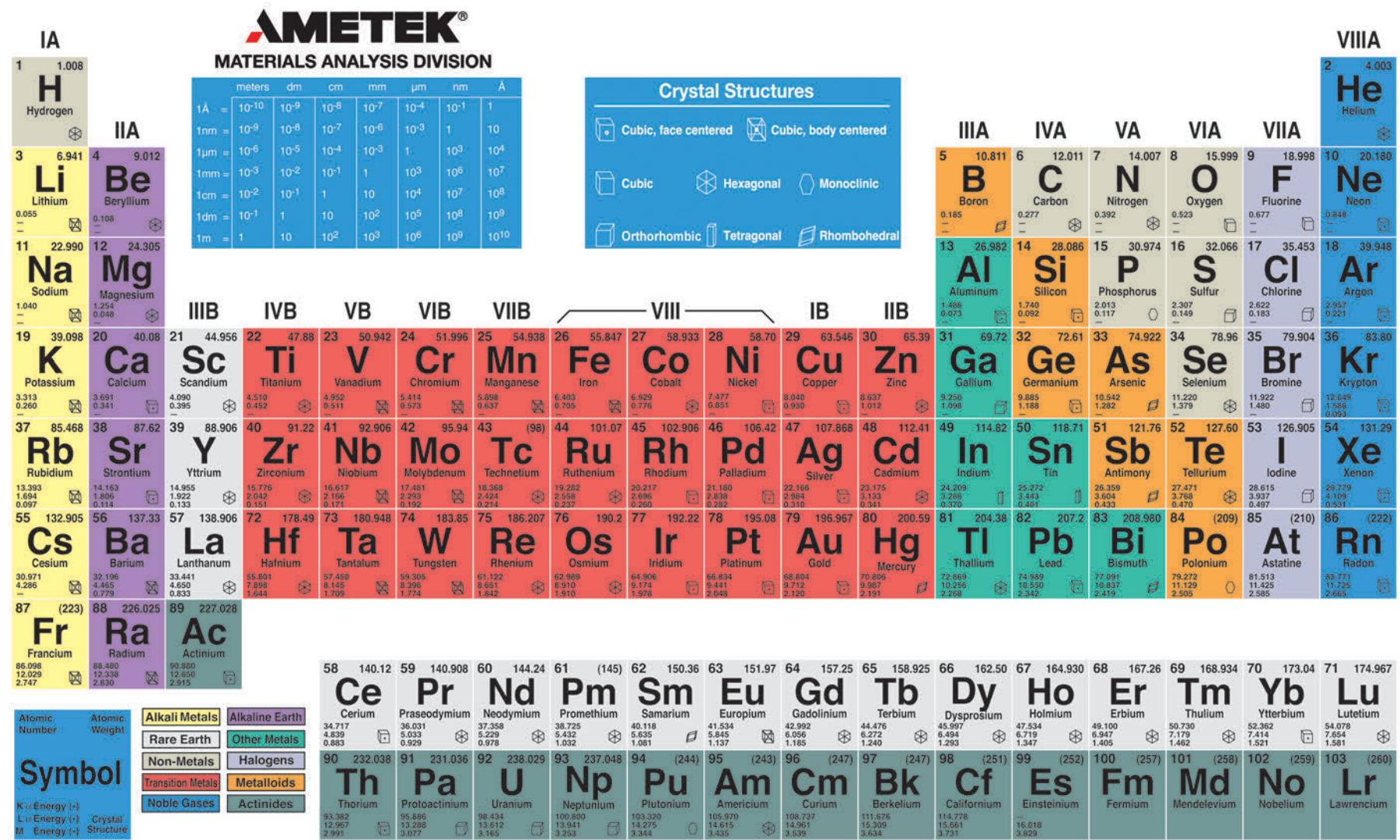
$L : K$

# EPFL Separation of EDX peaks



[<sup>λ</sup> Wavelength-dispersive X-ray spectroscopy (WDXS)]

# EPFL Periodic table of X-ray peaks



# EPFL Periodic table of X-ray peaks

Energy in keV

IIIA		IVA		VA		VIA		VIIA		2	4.003
5	10.811	6	12.011	7	14.007	8	15.999	9	18.998	He	Helium
B	Boron	C	Carbon	N	Nitrogen	O	Oxygen	F	Fluorine	Ne	Neon
0.185 — —	0.277 — —	0.392 — —	0.523 — —	0.677 — —	0.848 — —						
13	26.982	14	28.086	15	30.974	16	32.066	17	35.453	18	39.948
Al	Aluminum	Si	Silicon	P	Phosphorus	S	Sulfur	Cl	Chlorine	Ar	Argon
1.486 0.073 —	1.740 0.092 —	2.013 0.117 —	2.307 0.149 —	2.622 0.183 —	2.957 0.221 —						
31	69.72	32	72.61	33	74.922	34	78.96	35	79.904	36	83.80
Ga	Gallium	Ge	Germanium	As	Arsenic	Se	Selenium	Br	Bromine	Kr	Krypton
9.250 1.098 —	9.885 1.188 —	10.542 1.282 —	11.220 1.379 —	11.922 1.480 —	12.649 1.586 0.093						
49	114.82	50	118.71	51	121.76	52	127.60	53	126.905	54	131.29
In	Indium	Sn	Tin	Sb	Antimony	Te	Tellurium	I	Iodine	Xe	Xenon
24.209 3.286 0.370	25.272 3.443 0.401	26.359 3.604 0.433	27.471 3.768 0.470	28.615 3.937 0.497	29.779 4.109 0.531						

No X-ray  
because no 2s... e<sup>-</sup>  
only 1s

← K peak

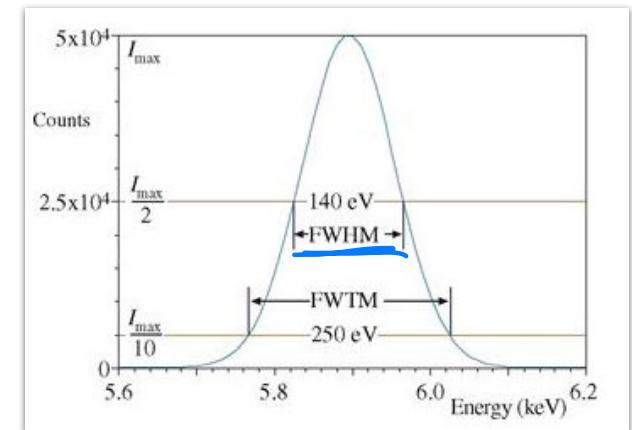
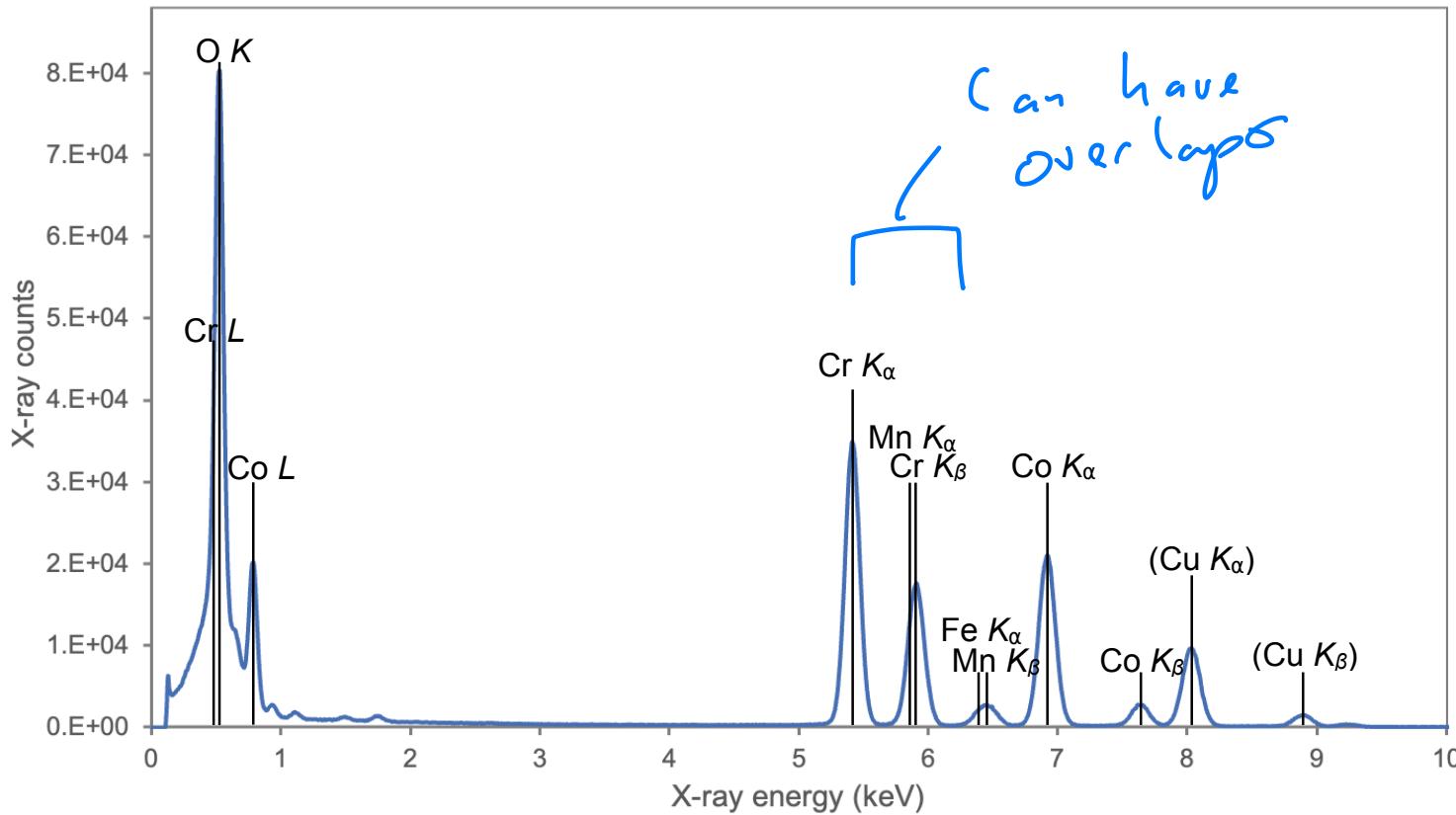
← K  
← L

← K  
← L  
← M

As 2↑  
X-ray engag↑  
because core-shell  
e<sup>-</sup> goes down  
to deeper level

# EPFL The EDX spectrum

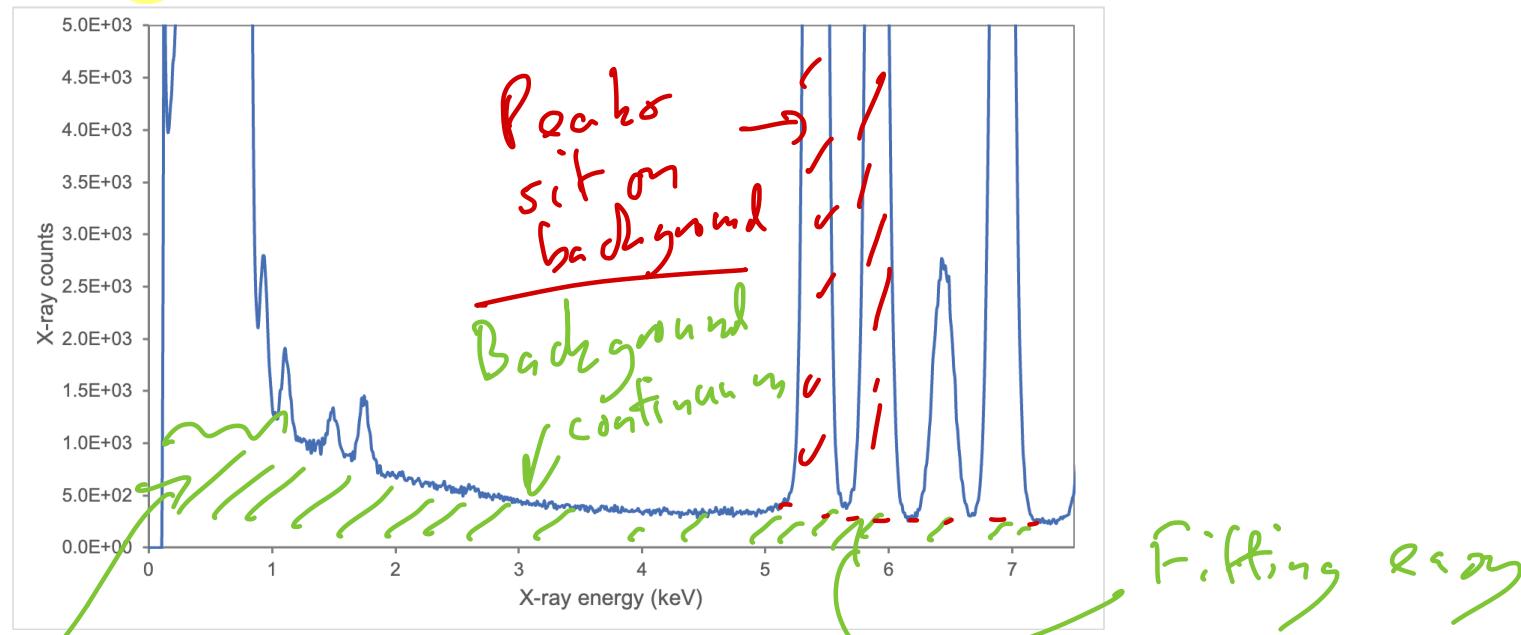
- Example spectrum from fuel cell sample containing O, Cr, Mn, Fe, Co
- Spectrum of mostly well-defined peaks that e.g. can be fitted with Gaussians



Widths of peak determined by detector typically 120 - 140 eV wide

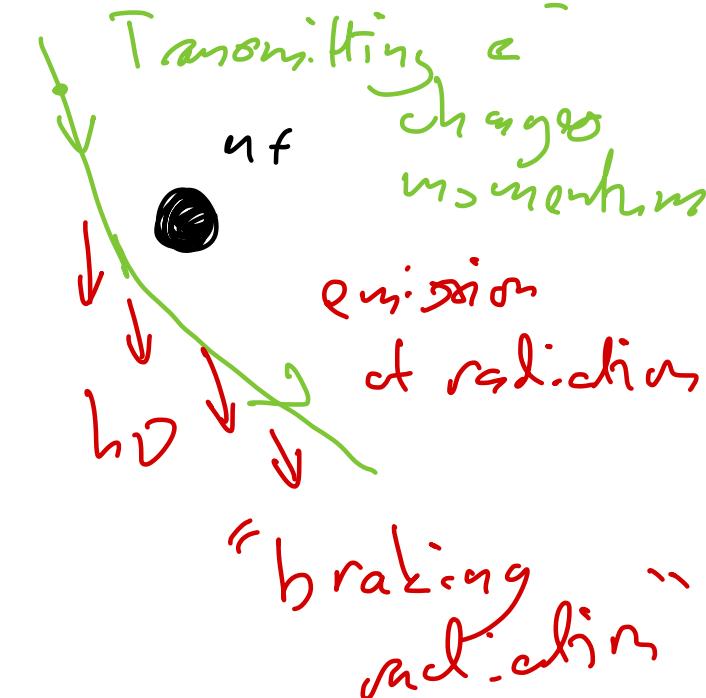
# EPFL Bremsstrahlung background

- Continuum background of radiation emitted when  $e^-$  velocity changed by atomic field
- Stronger at low keV; depends on atomic number  $Z$



Fitting challenge

$\beta_0, \beta_1, \beta_2$ : empirical values



$$\text{"State-of-the-art" model by Chapman (down to 1 keV): } I_{\text{brem}} = \frac{\beta_0}{E_{\text{X-ray}}} + \beta_1 + \beta_2 E_{\text{X-ray}}$$

# EPFL EDXS quantification

- To go from qualitative to quantitative: measure the intensities  $I_j$  of the X-ray peaks (area under the peak)
- Typically apply “Cliff-Lorimer” approach where calculate ratios of constituent elements:

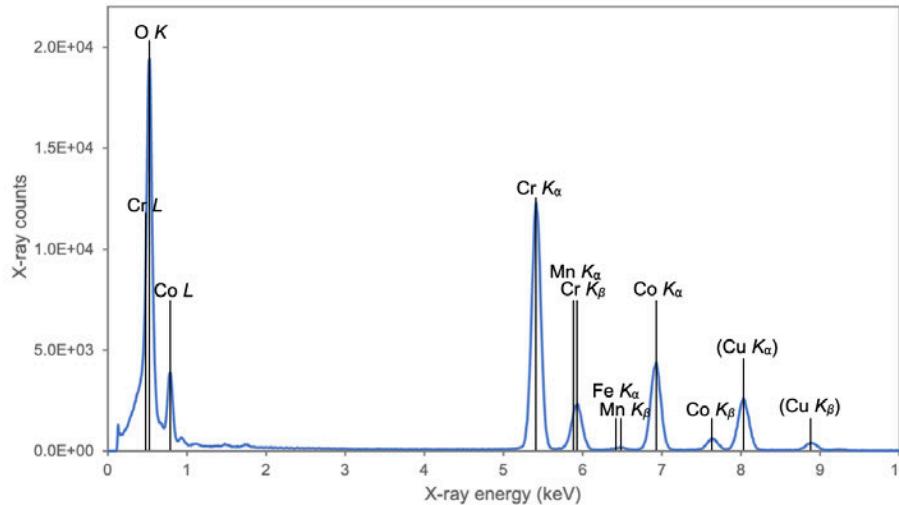
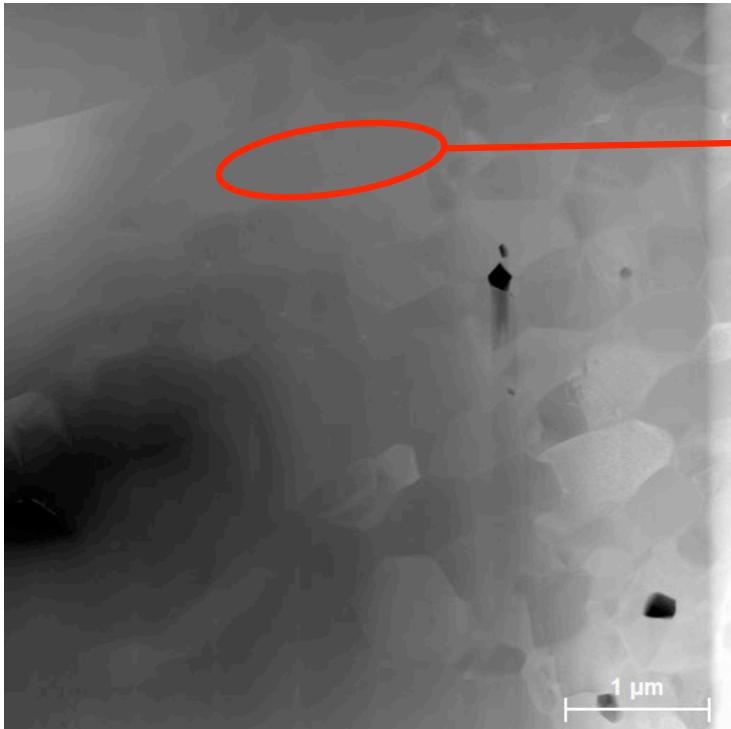
$$\frac{C_A}{C_B} = k_{AB} \frac{I_A}{I_B}$$

- $k_{AB}$ : k-factor
  - determined empirically by: standards / theoretical calculations / empirical models
- k-factors relate to probability of X-ray emission, probability of X-ray absorption and probability of unabsorbed X-ray being detected
- Rule of thumb: quantification accuracy 10–20%. However, much better (e.g. 1%) can be achieved in certain cases
- Detection limit: ~0.1 – a few at. %

# EPFL EDXS quantification

Spinel :  $AB_2O_4$   
A, B, transition metals  
 $\rightarrow 57\text{ at. \% O}$

- Example: Cr-rich grain in fuel cell spinel layer

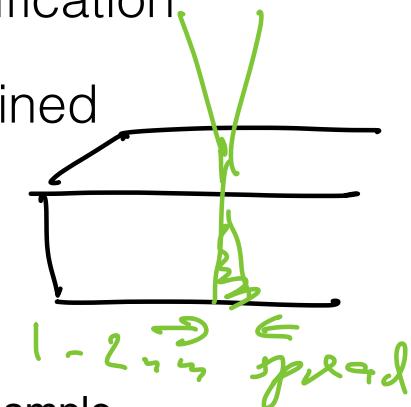


Element	Peak series	At. %
Cr	K	33.7
Co	K	13.8
Mn	K	2.5
Fe	K	0.1
O	K	49.9

Baker relative accuracy  
14% error

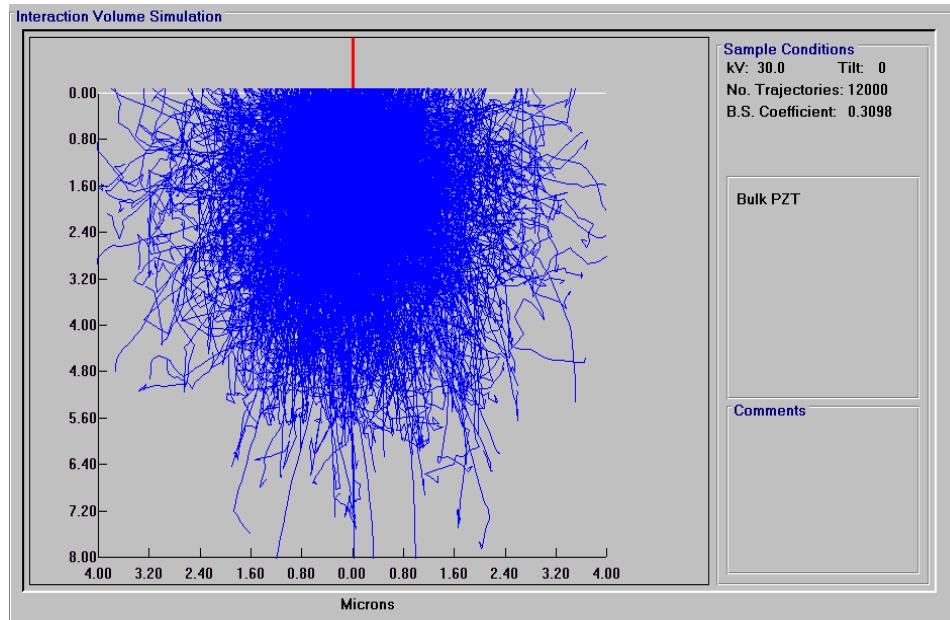
# EPFL Compared to SEM-EDXS

- (Can) Neglect correction factors for absorption and fluorescence in quantification
- High energy e-beam and thin sample  $\Rightarrow$  X-rays emitted from narrow/confined volume of sample in beam path direction

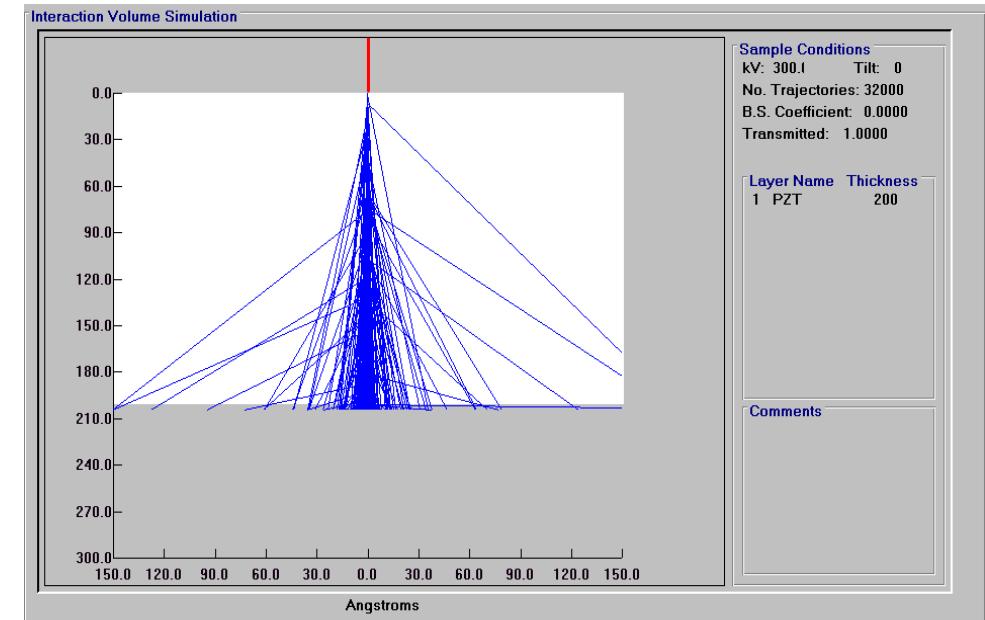


Pb(Zr,Ti)O<sub>3</sub> scattering models

SEM: 30 keV beam, bulk sample



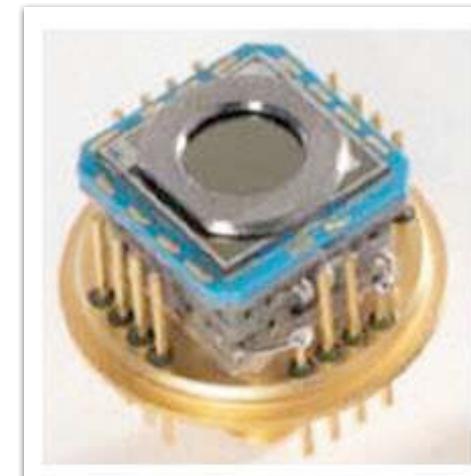
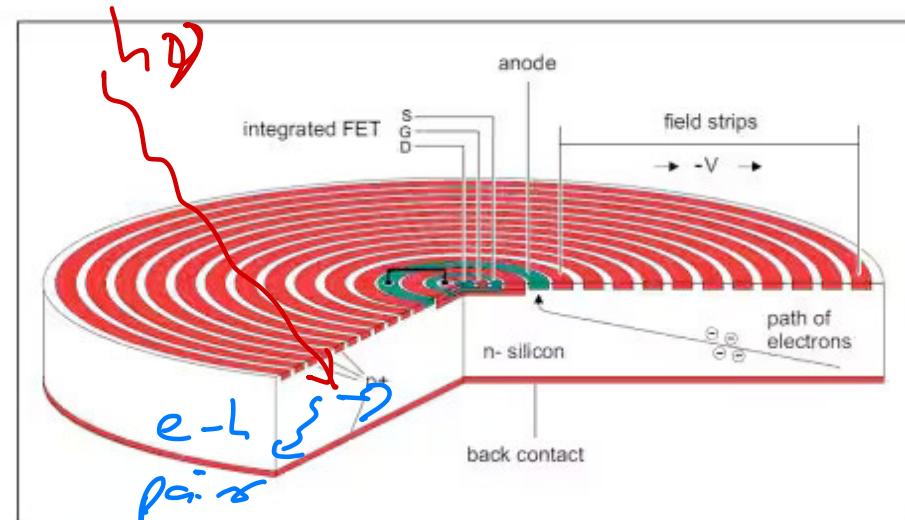
STEM: 300 keV beam, thin sample



# EPFL EDX detection

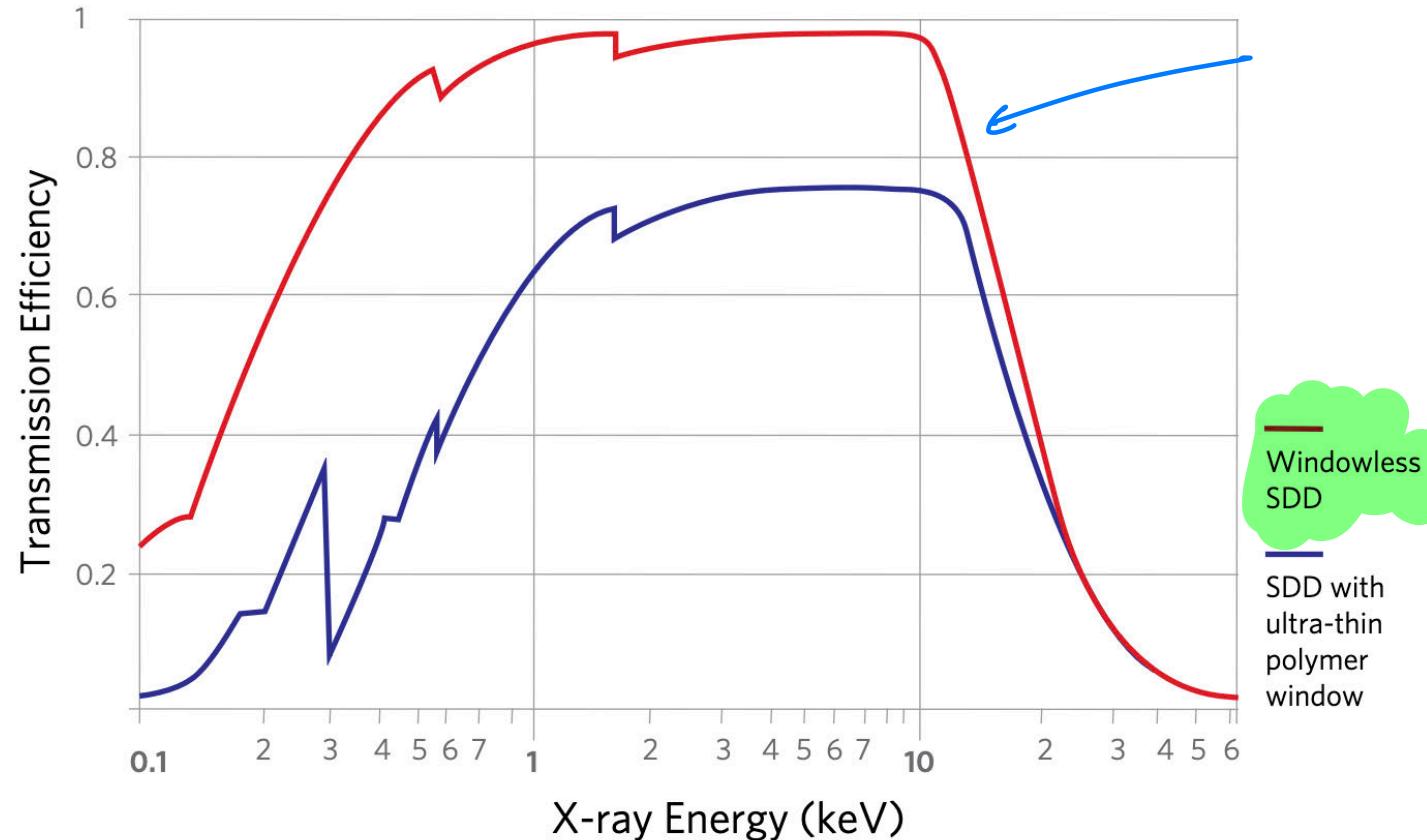
- Modern standard is the *Silicon Drift Detector (SDD)*
- Incident X-ray absorbed in Si creates  $e^-$ - $h^+$  pairs
- Internal electric field drifts  $e^-$  charge towards anode
- Accumulated charge converted to voltage by a pre-amplifier
- Quantity of charge carriers depends on X-ray energy  
⇒ measured voltage corresponds to energy of detected X-ray

Detectors ~ compact , v. fast



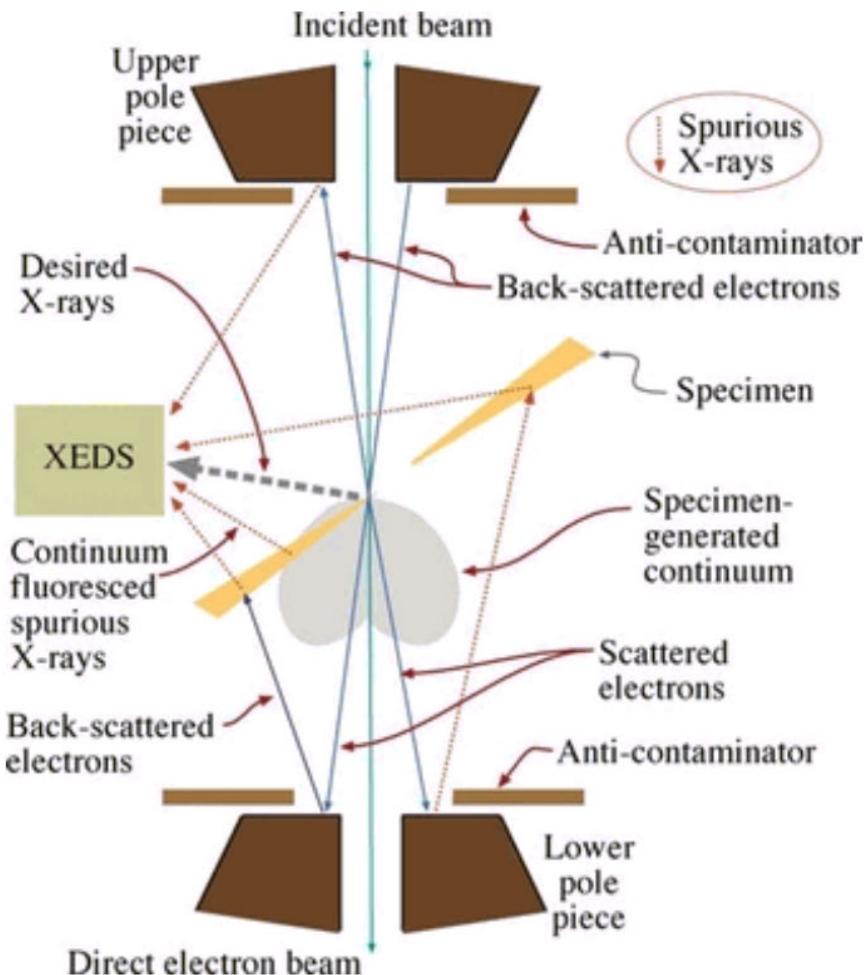
# EPFL Detective quantum efficiency (DQE)

- SDD detectors are compact and fast, but poor DQE for X-rays  $\gtrsim 20$  keV



Moorthy use 0-20 keV range

# EPFL Detection geometry

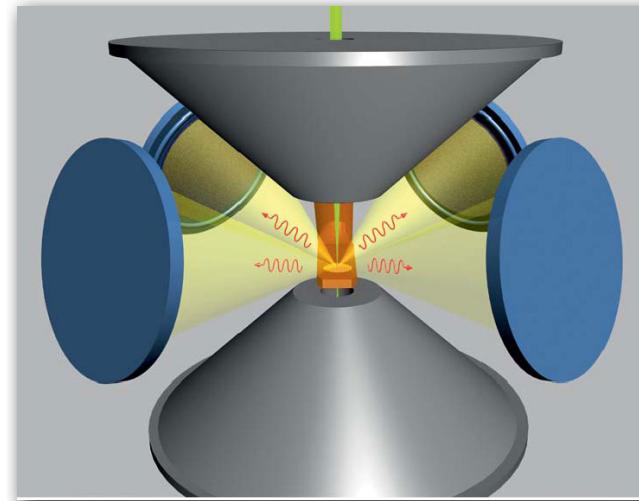


- Take care of spurious artefact X-ray peaks

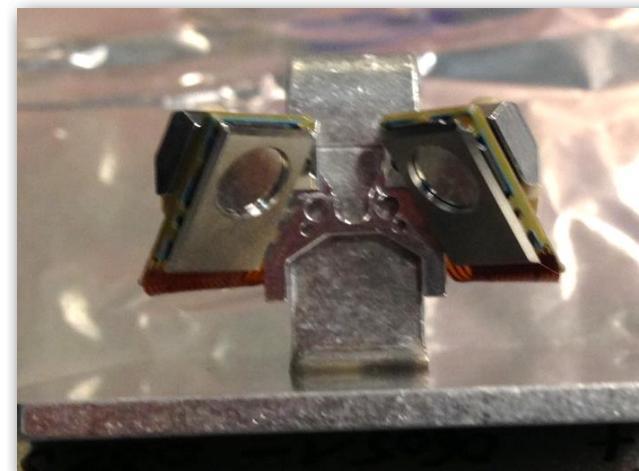
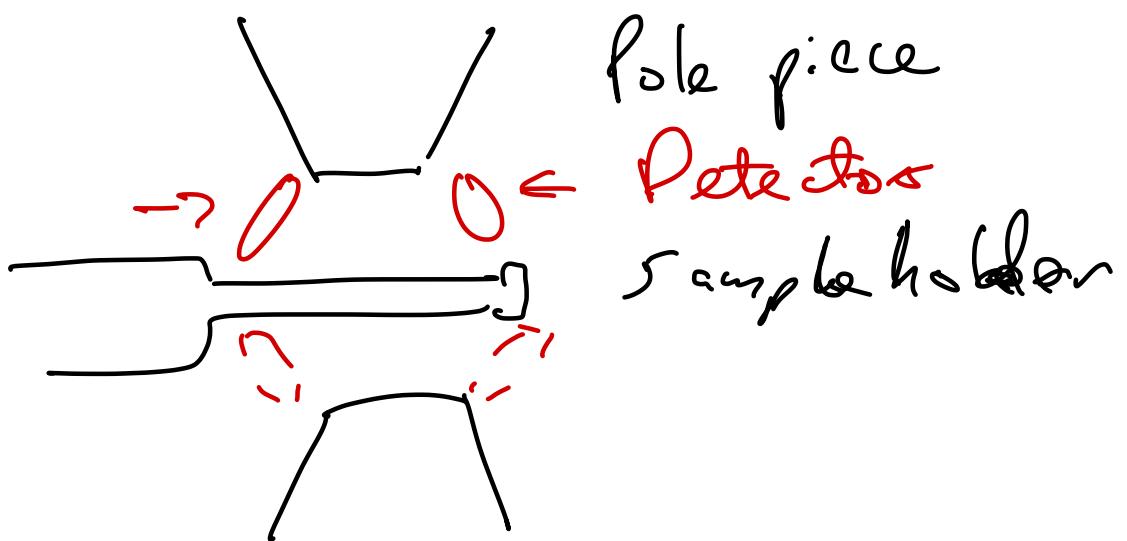
- Fluorescence of X-rays from support grid (e.g.  $\text{Ca K}_\alpha, \text{K}_\beta$ )  
- Pole piece ( $\text{Fe, Co, Cr}$ )?

# EPFL Detection geometry

SDD: up to 50'000 counts/s



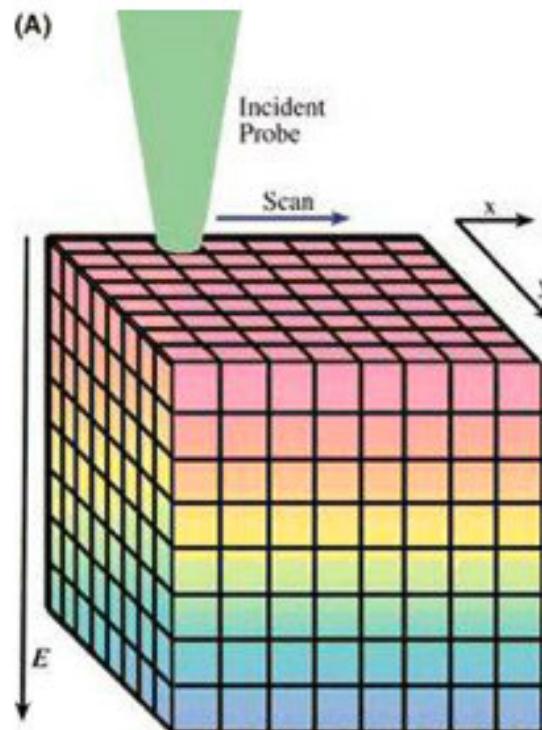
- New standard is to use multiple SDDs to increase solid angle of collection and hence detection efficiency
- For example: “Super-X” on Osiris, Titan with 4 quadrants giving  $\sim 1$  Sr solid angle of collection
- State-of-the-art: Thermo Fisher Scientific Ultra with  $\sim 4$  Sr



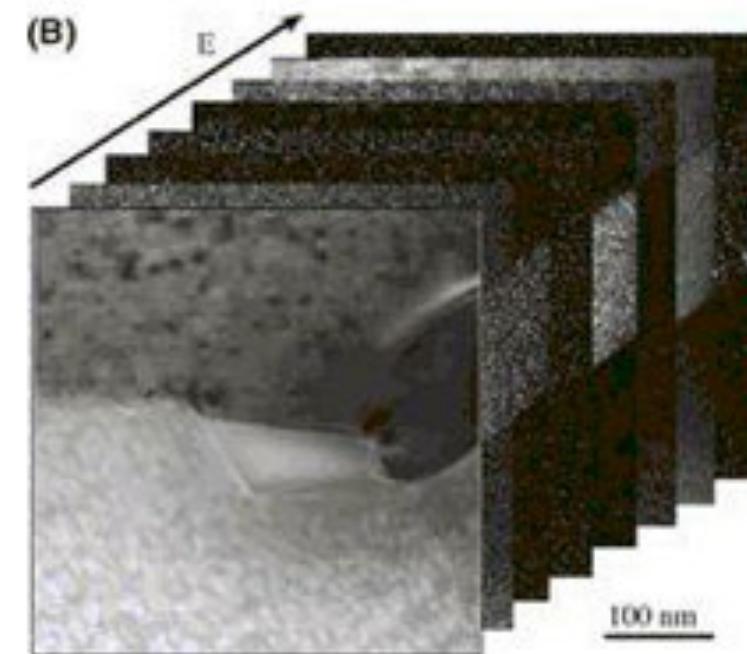
# EPFL STEM-EDXS data-cube

- EDXS map: acquire one spectrum per pixel position  $(x, y)$
- Gives 3D data-cube of information with axes  $(x, y, E)$
- Data can be post-processed – integrate area under peak to generate qualitative elemental map

*“Spectrum image”*



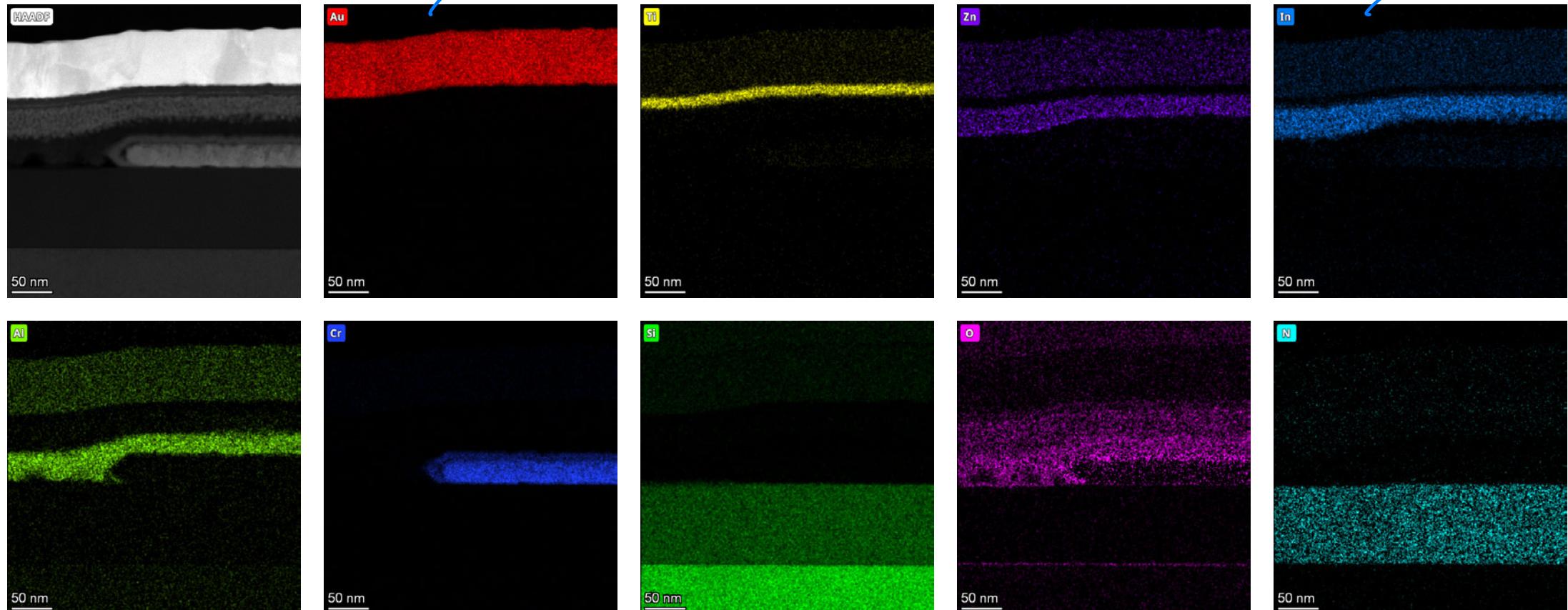
Each position  
 $(x, y)$   
→ Spectrum  
 $I$   
 $E(kV)$



# EPFL EDXS mapping: applications

- Multilayer sample – net counts maps

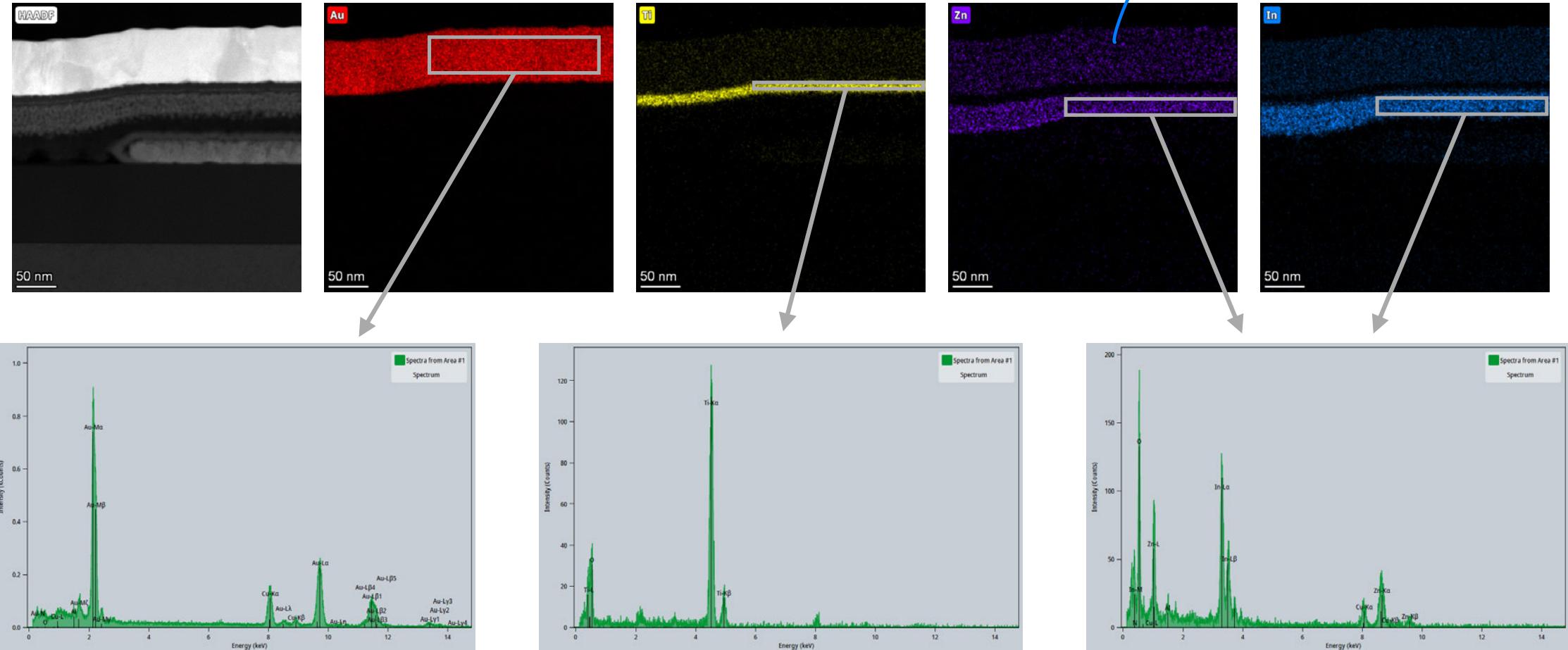
→ Extract integrated signal  
from peaks



# EPFL EDXS mapping: applications

- Multilayer sample – *integrated counts* EDX spectra

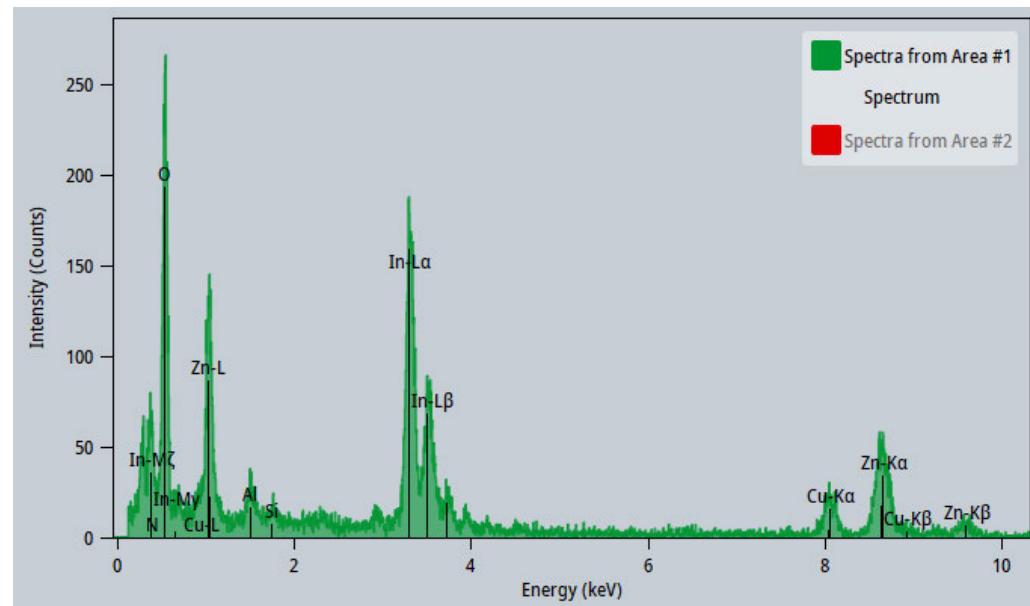
Fiducial signals from the motor background



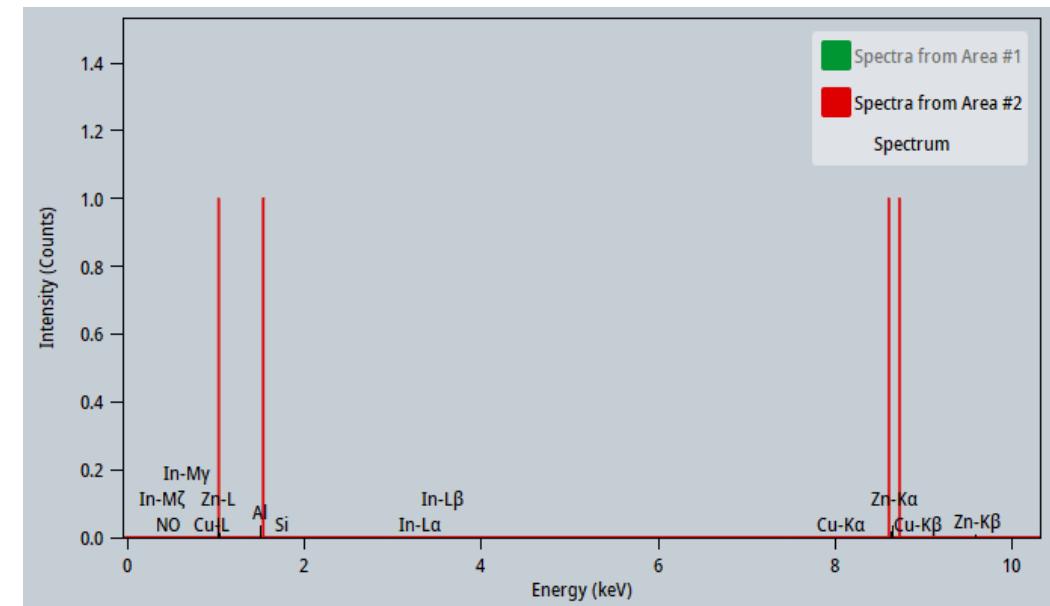
# EPFL Why integrate counts across spatial ROI?

- In-Zn-O layer:

Integrated from  $270 \times 25 = 6'750 \text{ px}^2$



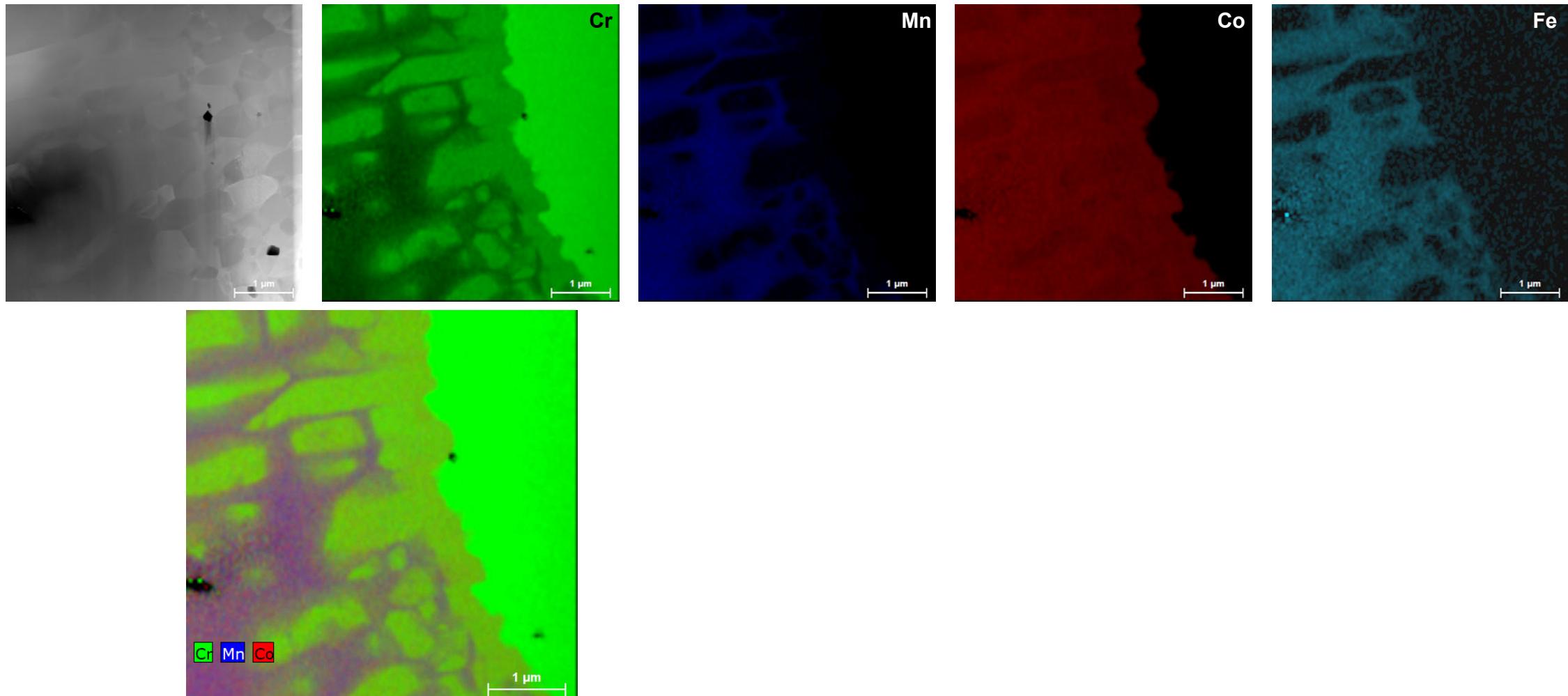
Single pixel spectrum



Photon statistics: peak with count  $N$   
 $n_{sig} = \sqrt{N}$   
 $\Rightarrow$  Need  $N = 10,000$  for 1% accuracy

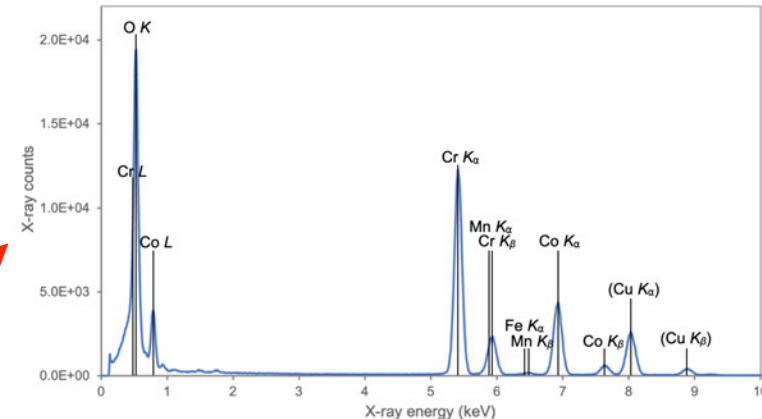
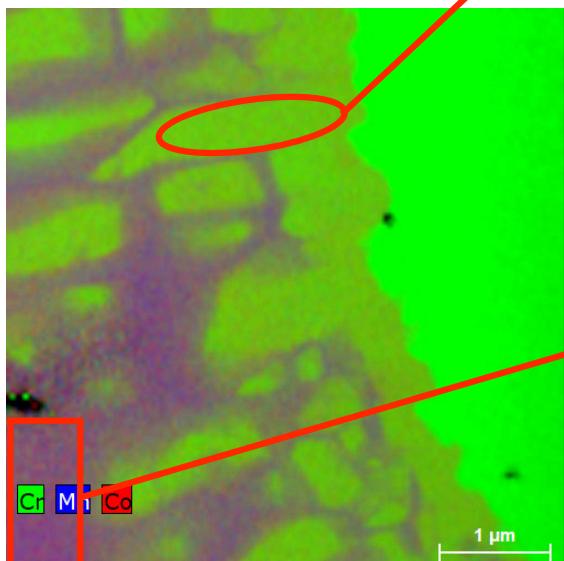
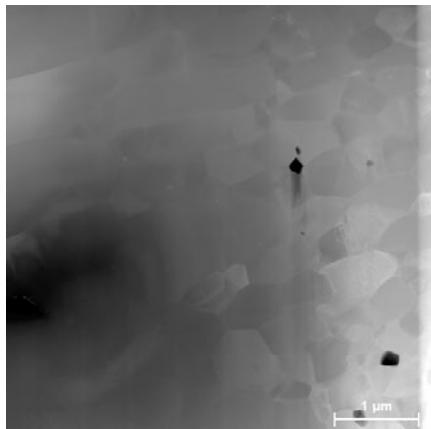
# EPFL EDXS mapping: applications

- Fuel cell sample: Fe-doped MnCo<sub>2</sub>O<sub>4</sub> spinel layer

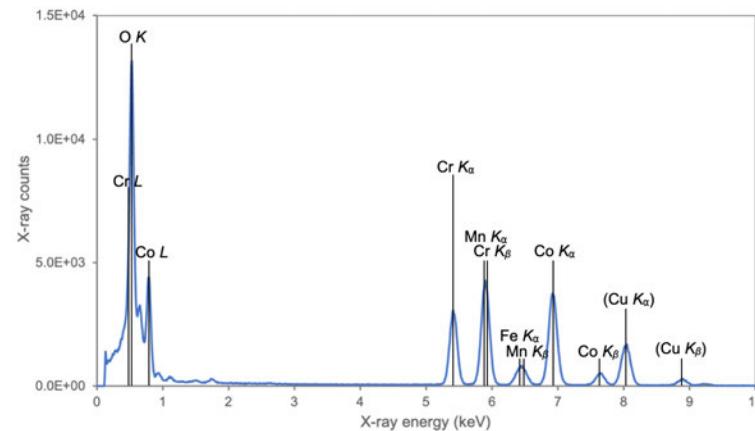


# EPFL EDXS mapping: applications

- Fuel cell sample: Fe-doped MnCo<sub>2</sub>O<sub>4</sub> spinel layer



Element	Peak series	At. %
Cr	K	33.7
Co	K	13.8
Mn	K	2.5
Fe	K	0.1
O	K	49.9



Element	Peak series	At. %
Cr	K	12.5
Co	K	18.3
Mn	K	17.2
Fe	K	2.2
O	K	49.8

# EPFL Atomic resolution EDXS with Cs-STEM

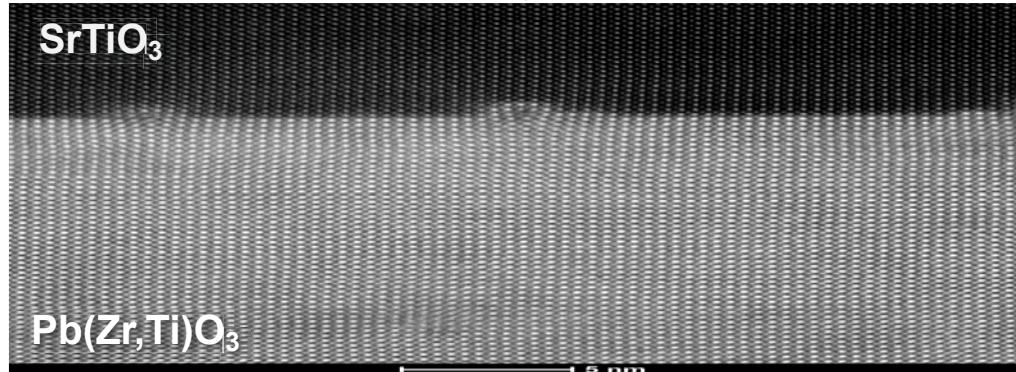
- Sample of  $\text{Pb}(\text{Zr},\text{Ti})\text{O}_3$  on  $\text{SrTiO}_3$



# EPFL Atomic resolution EDXS with Cs-STEM

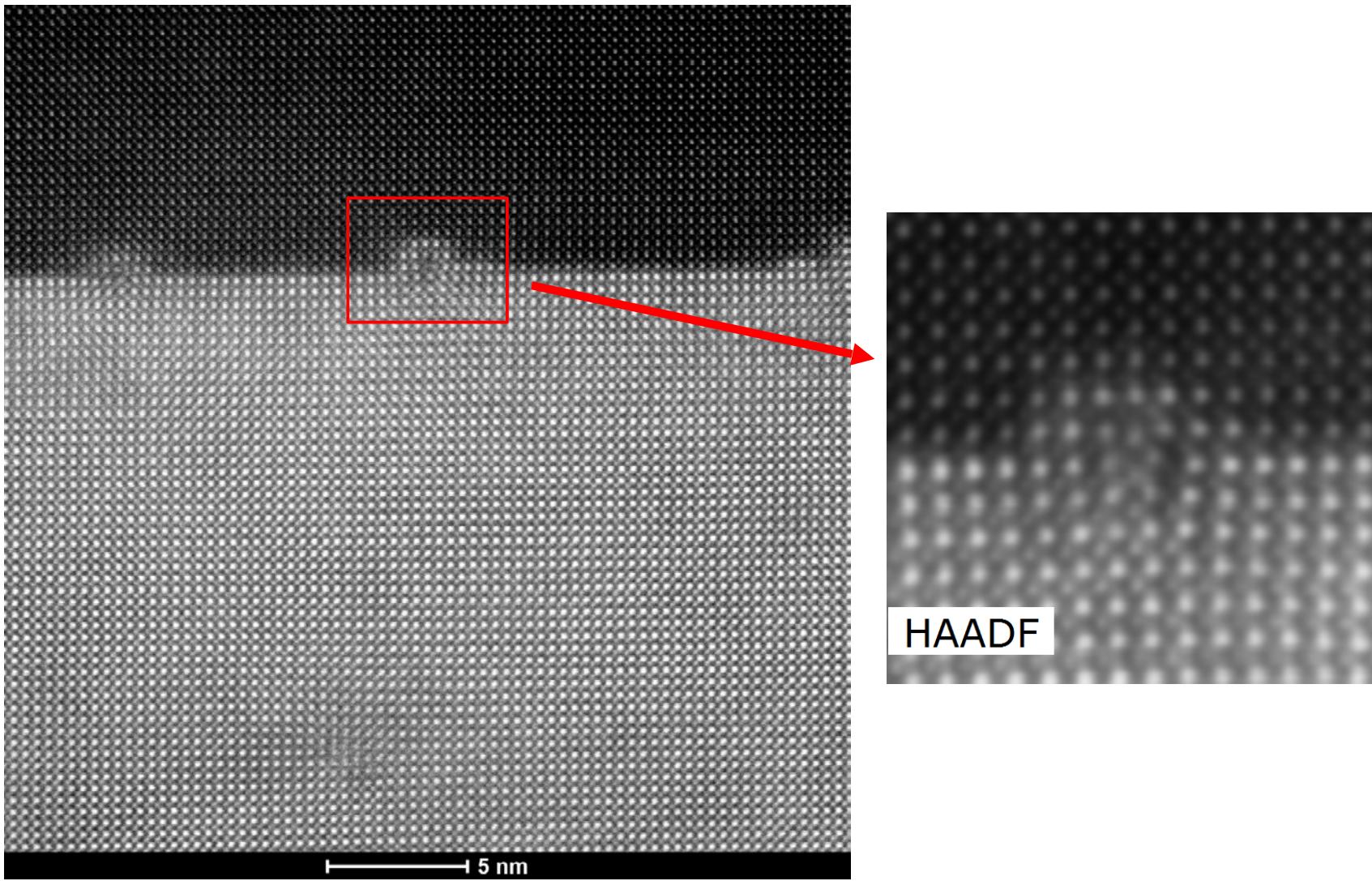
- Sample of  $\text{Pb}(\text{Zr},\text{Ti})\text{O}_3$  on  $\text{SrTiO}_3$

↓ Misfit dislocation



# EPFL Atomic resolution EDXS with Cs-STEM

- Sample of  $\text{Pb}(\text{Zr},\text{Ti})\text{O}_3$  on  $\text{SrTiO}_3$



# EPFL Atomic resolution EDXS with Cs-STEM

- Sample of  $\text{Pb}(\text{Zr},\text{Ti})\text{O}_3$  on  $\text{SrTiO}_3$  – atomic resolution elemental mapping

